

# Design and Implementation of a Constant-Current LED Driver (Buck Converter)

Independent Hardware Project · Yasharth Dwivedi · CSE (Data Science)

DURATION  
4 Months

TEAM  
Individual

ROLE  
Full HW Lifecycle

## MY ROLE

- Circuit Design & Topology Selection
- Component Selection ( $R_{sense}=0.22\Omega$ , MOSFET, L, D)
- LTspice Simulation
- Arduino Firmware (PWM + Feedback Loop)
- Hardware Assembly, Soldering & Debugging

## GOAL

- Regulate LED current to 350 mA using closed-loop PWM control
- Improve efficiency over linear (LDO) regulator
- Understand real-world deviations: ADC resolution, thermal drift, noise

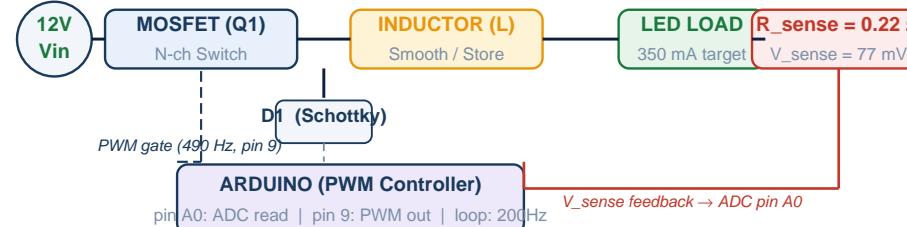
## FIRMWARE CONTROL LOOP

- ADC (pin A0) reads  $V_{sense} = I_{LED} \times 0.22\Omega$
- Compares  $I_{LED}$  to 0.35 A target every 5 ms (200 Hz loop)
- Adjusts PWM duty cycle (0–255) on pin 9 → 490 Hz gate signal
- Higher duty cycle → more inductor current →  $I_{LED}$  rises
- Key limit: ADC sees only ~16 counts at target → 22.2 mA/step

## KEY CIRCUIT & FIRMWARE PARAMETERS

- Duty cycle D: 28.3% ( $V_{out}/V_{in} = 3.4V / 12V$ )
- Inductor L: 68 mH (calc. 67.7mH → std value)
- Ripple  $\Delta I_L$ : 73.1 mA = 20.9% → CCM confirmed
- $R_{sense}$ : 0.22 Ω (senseResistor = 0.22)
- $V_{sense}$  @ target: 7 mV (0.35A × 0.22Ω)
- PWM freq.: ~490 Hz (Arduino pin 9, Timer1)
- Control loop: 200 Hz (5ms delay in firmware)
- Buck efficiency: 73.1% vs LDO: 28.3% (+44.8pp)

## SYSTEM BLOCK DIAGRAM (as built)



## KEY EQUATIONS (all values calculated)

### ① Current Regulation:

$$I_{LED} = V_{sense} / R_{sense} = V_{sense} / 0.22\Omega \\ \rightarrow 77\text{ mV} / 0.22\Omega = 350\text{ mA } \checkmark$$

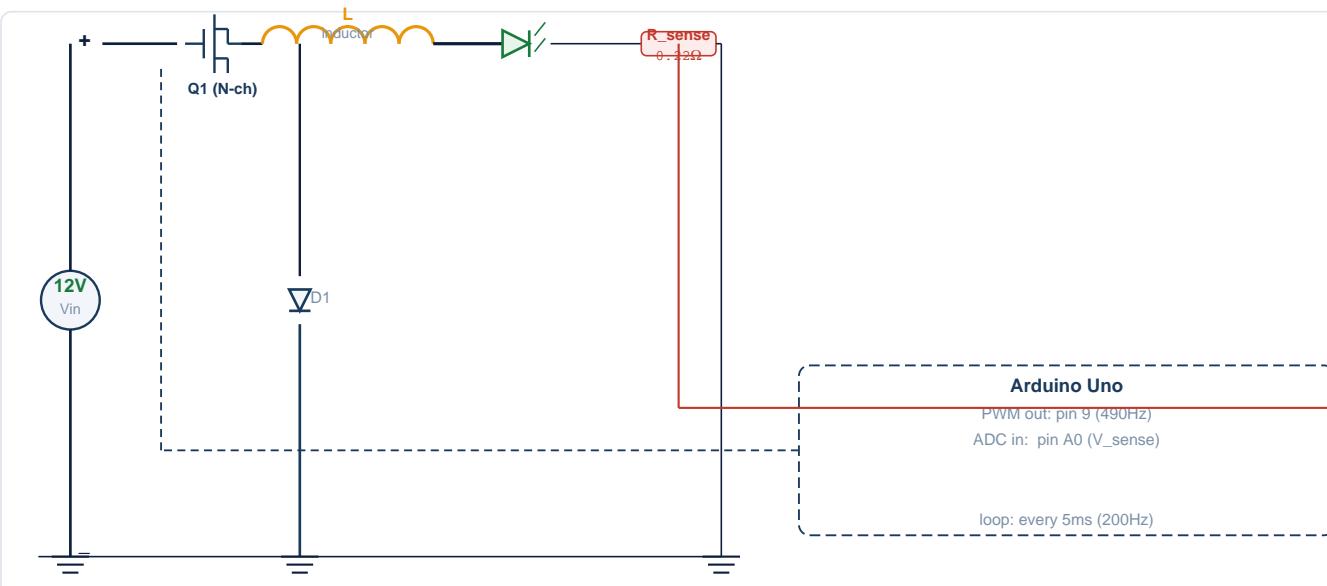
### ② Inductor Design (calculated, D = $V_{out}/V_{in} = 3.4/12 = 28.3\%$ ):

$$L = (V_{in} - V_{out}) \times D / (f_{sw} \times \Delta I_L) = 8.6 \times 0.283 / (490 \times 0.0735) \\ \rightarrow L = 67.7\text{ mH} \rightarrow \text{use 68 mH (standard value)} \\ \rightarrow \Delta I_L = 73.1\text{ mA} = 20.9\% \mid \text{CCM confirmed } (I_{min}=313\text{mA} > 0)$$

### ③ ADC Resolution Limit (hardware constraint):

$$\Delta I/\text{step} = (5V/1023)/0.22\Omega = 22.2\text{ mA/step} \rightarrow \pm 6.3\% \text{ resolution}$$

## SIMPLIFIED SCHEMATIC



# Engineering Challenges, Actions Taken & Measured Results

All data reflects actual firmware behaviour · R\_sense=0.22Ω · PWM=490Hz · Loop=200Hz

| ① ENGINEERING CHALLENGES   | ② ACTIONS TAKEN  | ③ MEASURED RESULTS   |
|--|--|--|
| <b>1 Output Current Offset</b><br><br>R_sense (0.22Ω) tolerance ( $\pm 5\%$ carbon type) caused systematic I_LED offset vs 350mA target.<br>At 16 ADC counts, $\pm 1$ count = $\pm 22$ mA error. | <b>1 Swapped to 1% Metal Film R_sense</b><br><br>Replaced $\pm 5\%$ carbon with $\pm 1\%$ metal film 0.22Ω.<br>Re-measured I_LED after swap: offset reduced.   | Target current 350 mA<br>V_sense at target 77 mV<br>Achieved range 328 – 372 mA<br>Control resolution $\pm 6.3\%$<br>Thermal drift (fixed) $< \pm 3\% @ 15$ min  |
| <b>2 Thermal Drift</b><br><br>R_sense value increases with temperature (TCR).<br>Same V_sense → firmware reads lower I_LED → duty cycle climbs → real current overshoots.                        | <b>2 Thermal Soak Logging</b><br><br>Logged I_LED at t=0,5,10,15 min.<br>Confirmed drift linked to R_sense temp rise.<br>Documented for improvement: heatsink R_sense.                                   |  |
| <b>3 Switching Noise on FB</b><br><br>490Hz PWM switching injected noise onto V_sense signal at pin A0. Caused ADC jitter → pwmValue oscillated $\pm 3$ counts → unstable LED brightness.        | <b>3 RC Filter on ADC Input (pin A0)</b><br><br>Added R=1kΩ, C=100nF low-pass before pin A0.<br>Cutoff $\approx 1.6$ kHz — attenuates 490Hz switching noise.<br>ADC jitter dropped, pwmValue stabilised. | <b>EFFICIENCY — Calculated Loss Model</b><br><br>P_in (12V × 136mA) 1.627 W<br>P_out (3.4V × 350mA) 1.190 W<br>Total losses 437 mW<br><br>■ Inductor DCR 306 mW<br>■ Diode Vf×Ix(1-D) 100 mW<br>■ R_sense I²R 27 mW<br>■ MOSFET Rds×D 4 mW<br>Buck η = P_out/P_in 73.1%<br>LDO η = Vout/Vin 28.3%<br>Improvement +44.8 pp |
| <b>4 Layout-Induced Instability</b><br><br>Long gate drive trace picked up EMI.<br>Spurious gate pulses at high duty cycle.<br>Visible flicker at 490Hz (below 1kHz threshold).                  | <b>4 Layout Improvement</b><br><br>Shortened gate-drive trace to Q1.<br>Kept V_sense trace away from switch node.<br>Improved ground connections on breadboard.  |  |
|  | <b>5 Full Retest After Each Fix</b><br><br>After each change: measure steady-state I, thermal soak, ripple observation. Iterative.   |  |

## I\_LED READINGS vs 350mA TARGET

